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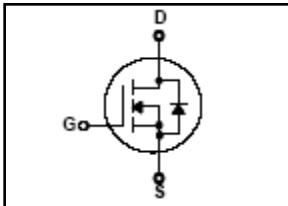
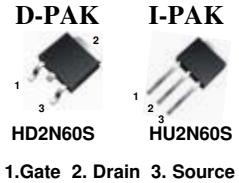
Nov 2007

## HD2N60 / HU2N60 600V N-Channel MOSFET

$BV_{DSS} = 600\text{ V}$   
 $R_{DS(on)\text{ typ}} = 4.2\text{ }\Omega$   
 $I_D = 1.9\text{ A}$

### FEATURES

- Originative New Design
- Superior Avalanche Rugged Technology
- Robust Gate Oxide Technology
- Very Low Intrinsic Capacitances
- Excellent Switching Characteristics
- Unrivalled Gate Charge : 6.0 nC (Typ.)
- Extended Safe Operating Area
- Lower  $R_{DS(ON)}$  : 4.2  $\Omega$  (Typ.) @  $V_{GS}=10\text{V}$
- 100% Avalanche Tested



### Absolute Maximum Ratings $T_C=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Value	Units
$V_{DSS}$	Drain-Source Voltage	600	V
$I_D$	Drain Current – Continuous ( $T_C = 25^\circ\text{C}$ )	1.9	A
	Drain Current – Continuous ( $T_C = 100^\circ\text{C}$ )	1.14	A
$I_{DM}$	Drain Current – Pulsed (Note 1)	7.6	A
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	120	mJ
$I_{AR}$	Avalanche Current (Note 1)	1.9	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	4.4	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	4.5	V/ns
$P_D$	Power Dissipation ( $T_A = 25^\circ\text{C}$ ) *	2.5	W
	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above 25°C	44	W
		0.35	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

### Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	2.87	$^\circ\text{C/W}$
$R_{\theta JA}$	Junction-to-Ambient*	--	50	
$R_{\theta JA}$	Junction-to-Ambient	--	110	

\* When mounted on the minimum pad size recommended (PCB Mount)

### **Electrical Characteristics** $T_{\text{C}}=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Type	Max	Units
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## On Characteristics

$V_{GS}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	2.0	--	4.0	$V$
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS} = 10 V$ , $I_D = 0.95 A$	--	4.2	5.0	$\Omega$

## Off Characteristics

$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to 25°C	--	0.6	--	V/°C
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	--	--	1	$\mu\text{A}$
		$V_{DS} = 480 \text{ V}, T_C = 125 \text{ °C}$	--	--	10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$	--	--	-100	nA

# Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$	--	280	365	pF
$C_{oss}$	Output Capacitance		--	37	48	pF
$C_{rss}$	Reverse Transfer Capacitance		--	6.0	8.0	pF

## Switching Characteristics

$t_{d(on)}$	Turn-On Time	$V_{DS} = 300\text{ V}$ , $I_D = 2.0\text{ A}$ , $R_G = 25\text{ }\Omega$ (Note 4,5)	--	9	28	ns
$t_r$	Turn-On Rise Time		--	25	60	ns
$t_{d(off)}$	Turn-Off Delay Time		--	24	58	ns
$t_f$	Turn-Off Fall Time		--	28	66	ns
$Q_g$	Total Gate Charge	$V_{DS} = 480\text{V}$ , $I_D = 2.0\text{ A}$ , $V_{GS} = 10\text{ V}$ (Note 4,5)	--	6.0	8.0	nC
$Q_{gs}$	Gate-Source Charge		--	1.3	--	nC
$Q_{gd}$	Gate-Drain Charge		--	2.6	--	nC

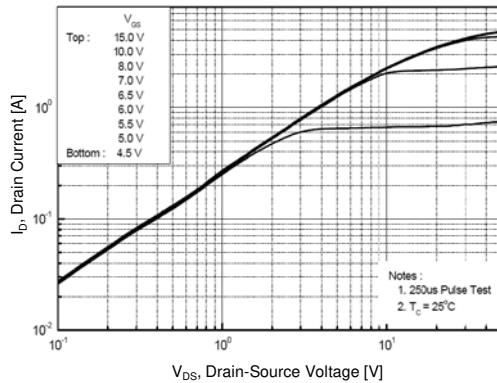
## Source-Drain Diode Maximum Ratings and Characteristics

$I_S$	Continuous Source-Drain Diode Forward Current		--	--	1.9	A
$I_{SM}$	Pulsed Source-Drain Diode Forward Current		--	--	7.6	
$V_{SD}$	Source-Drain Diode Forward Voltage	$I_S = 1.9 \text{ A}, V_{GS} = 0 \text{ V}$	--	--	1.4	V
$t_{rr}$	Reverse Recovery Time	$I_S = 2.0 \text{ A}, V_{GS} = 0 \text{ V}$	--	230	--	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt = 100 \text{ A}/\mu\text{s}$ (Note 4)	--	1.0	--	$\mu\text{C}$

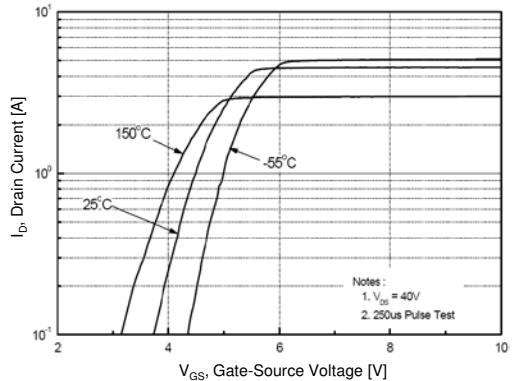
### **Notes :**

1. Repetitive Rating : Pulse width limited by maximum junction temperature
  2.  $L=56\text{mH}$ ,  $I_{AS}=2.0\text{A}$ ,  $V_{DD}=50\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$
  3.  $I_{SD} \leq 1.9\text{A}$ ,  $dI/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J=25^\circ\text{C}$
  4. Pulse Test : Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
  5. Essentially Independent of Operating Temperature

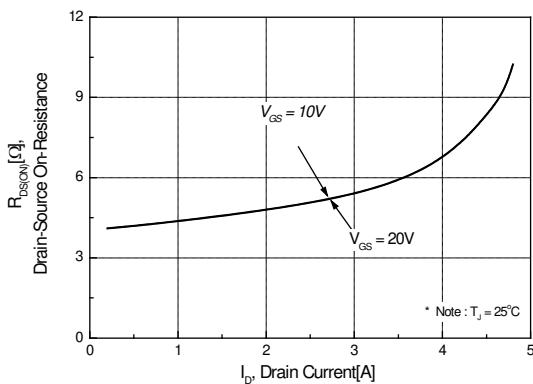
## Typical Characteristics



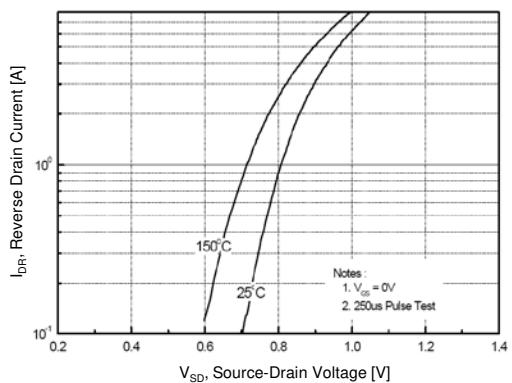
**Figure 1. On Region Characteristics**



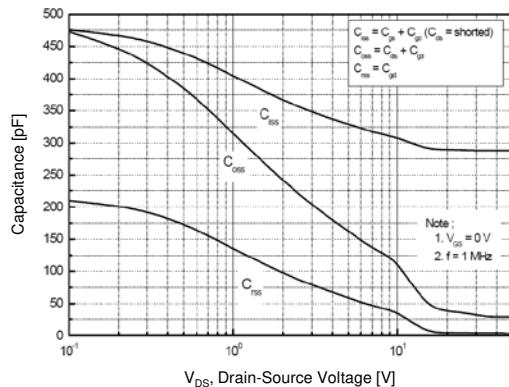
**Figure 2. Transfer Characteristics**



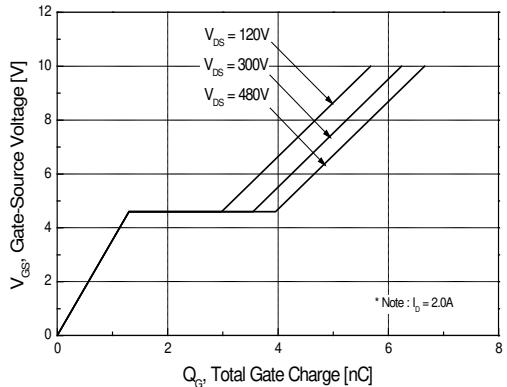
**Figure 3. On Resistance Variation vs. Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**

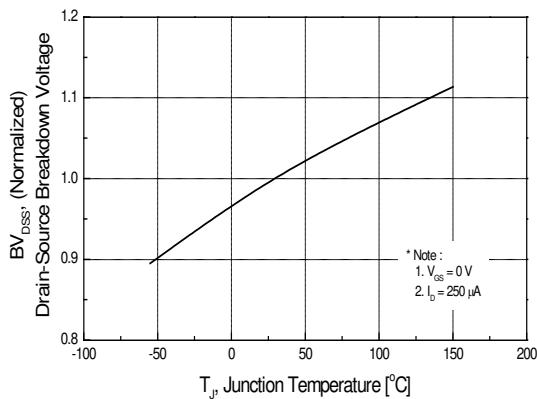


**Figure 5. Capacitance Characteristics**

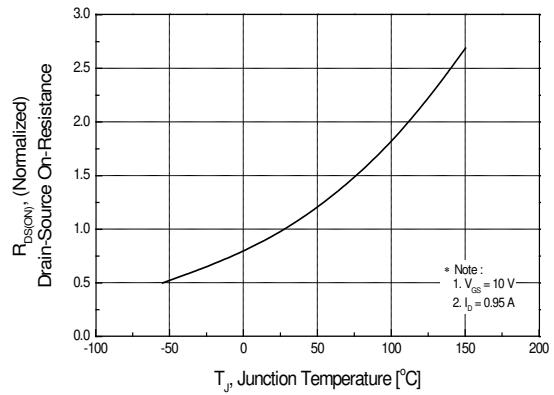


**Figure 6. Gate Charge Characteristics**

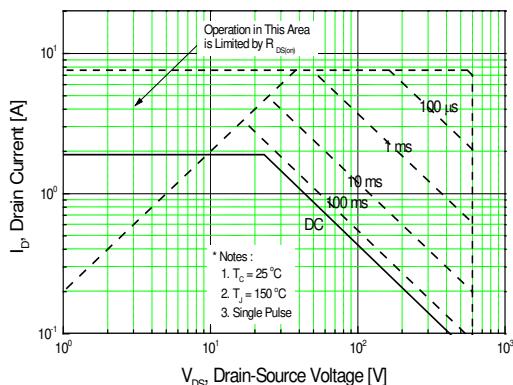
## Typical Characteristics (continued)



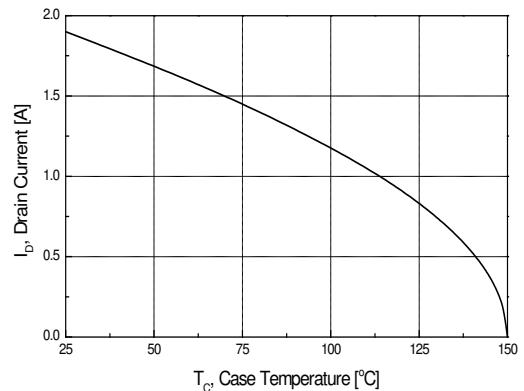
**Figure 7. Breakdown Voltage Variation vs Temperature**



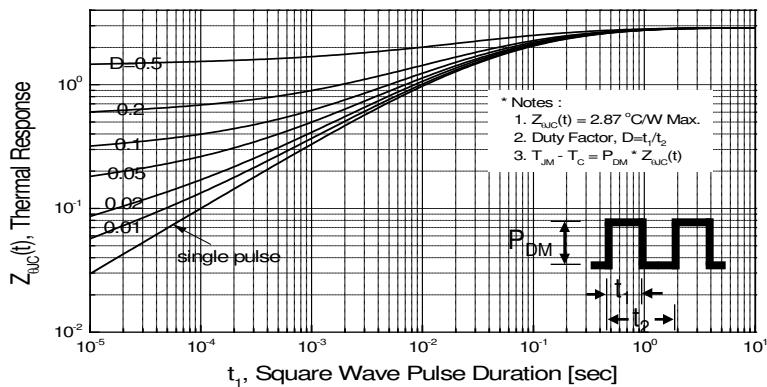
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Maximum Drain Current vs Case Temperature**



**Figure 11. Transient Thermal Response Curve**

Fig 12. Gate Charge Test Circuit &amp; Waveform

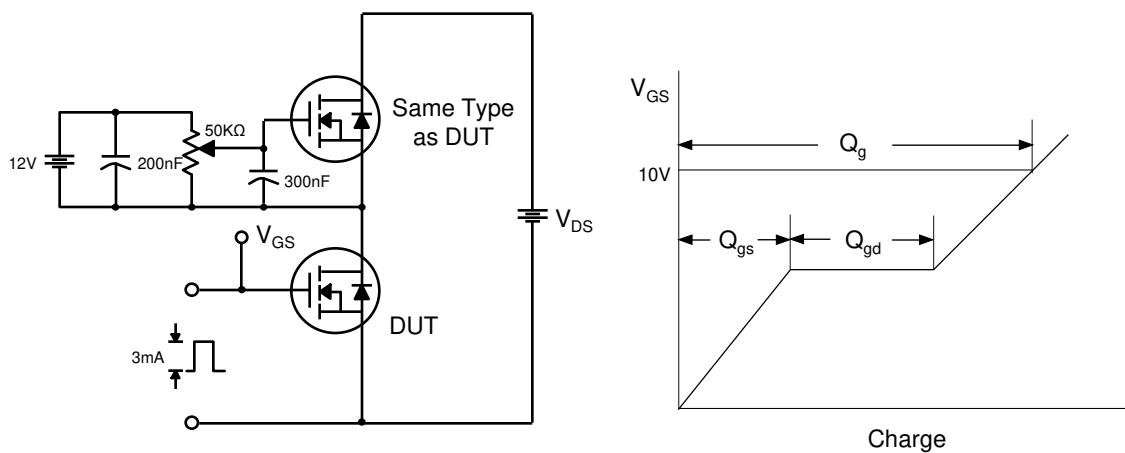


Fig 13. Resistive Switching Test Circuit &amp; Waveforms

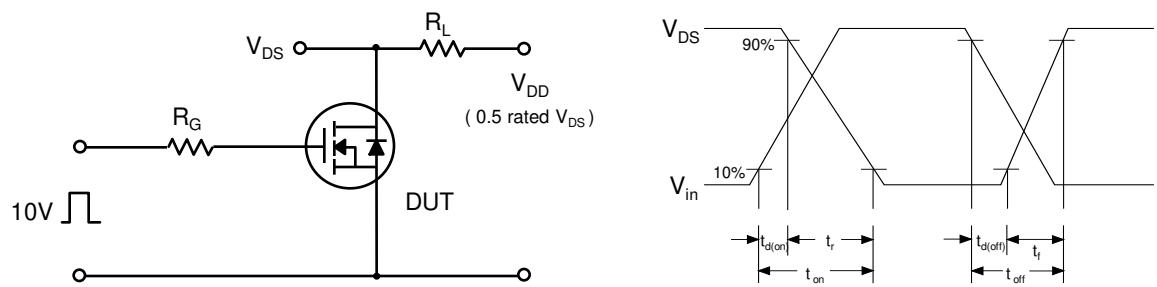


Fig 14. Unclamped Inductive Switching Test Circuit &amp; Waveforms

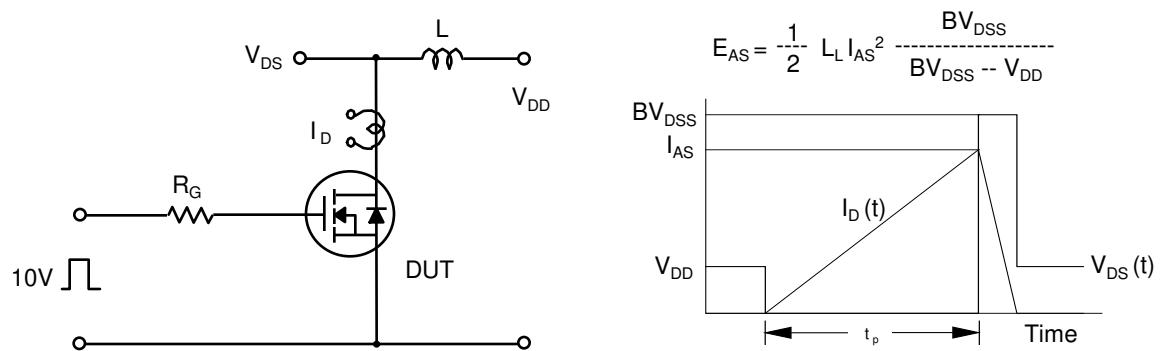
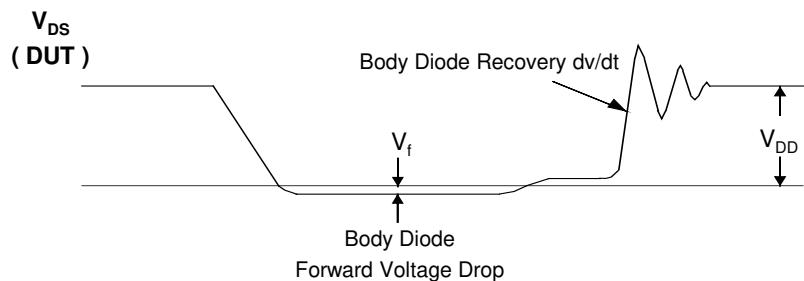
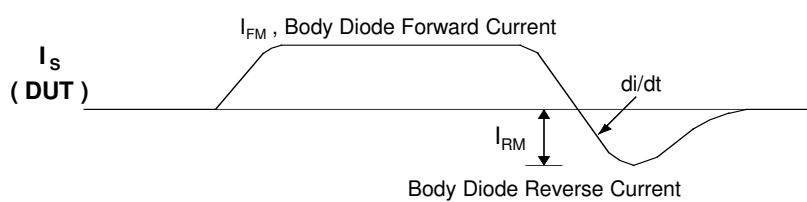
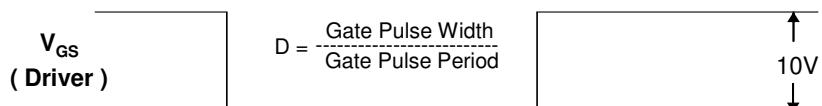
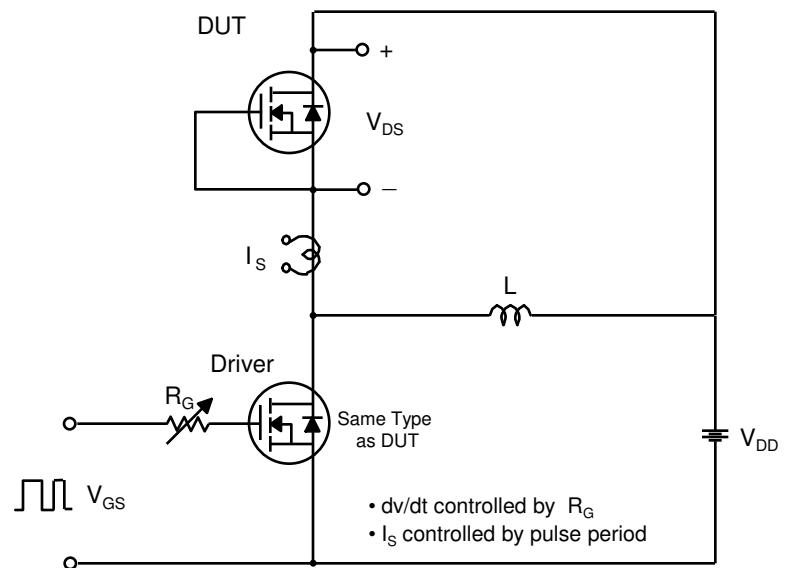
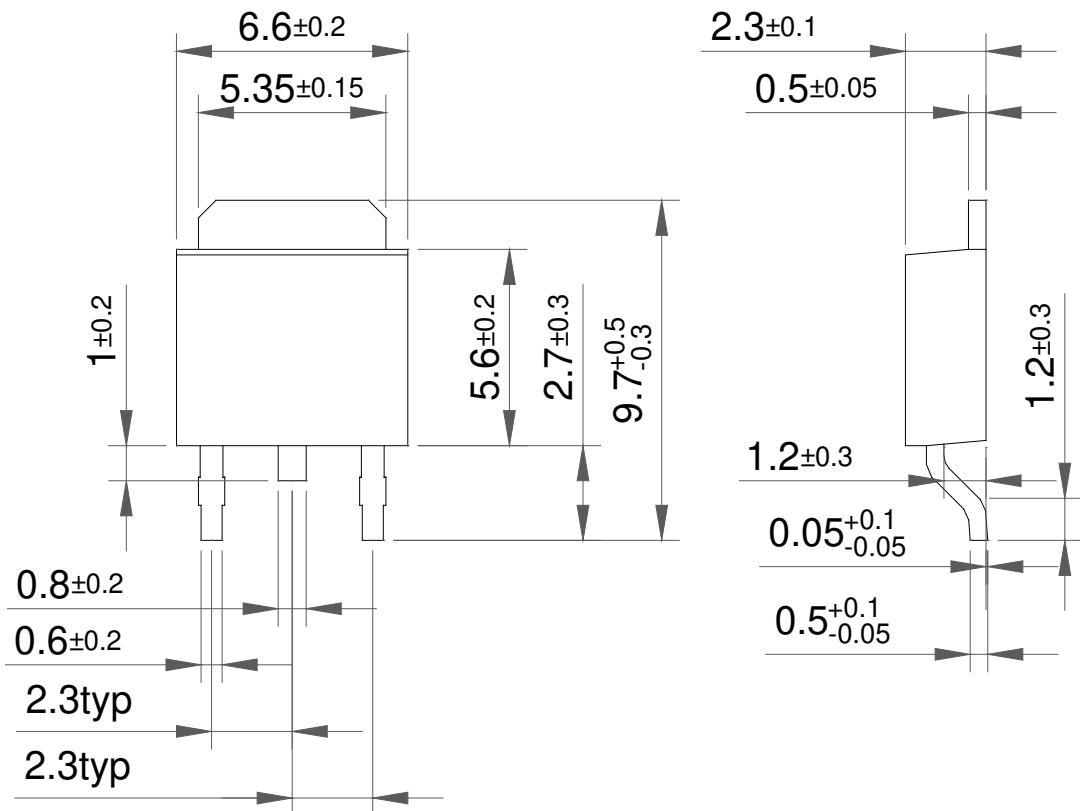


Fig 15. Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms



**Package Dimension****TO-252**

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